

Notice of Allowability

Application No.

10/724,694

Examiner

Elizabeth A. Rielley

Applicant(s)

MIYAJI ET AL.

Art Unit

2879

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address--

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. **THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS.** This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

1. ☒ This communication is responsive to a request for continued examination dated 4/11/2006.
2. ☒ The allowed claim(s) is/are 1-16.
3. ☒ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
 - a) ☒ All b) ☐ Some* c) ☐ None of the:
 1. ☒ Certified copies of the priority documents have been received.
 2. ☐ Certified copies of the priority documents have been received in Application No. _____.
 3. ☐ Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).

* Certified copies not received: _____.

Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.

THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.

4. ☐ A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.
5. ☐ CORRECTED DRAWINGS (as "replacement sheets") must be submitted.
 - (a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached
 - 1) ☐ hereto or 2) ☐ to Paper No./Mail Date _____.
 - (b) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date _____.Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).
6. ☐ DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

Attachment(s)

1. ☒ Notice of References Cited (PTO-892)
2. ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/08), Paper No./Mail Date _____
4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material
5. ☐ Notice of Informal Patent Application (PTO-152)
6. ☐ Interview Summary (PTO-413), Paper No./Mail Date _____
7. ☐ Examiner's Amendment/Comment
8. ☒ Examiner's Statement of Reasons for Allowance
9. ☐ Other _____

DETAILED ACTION

Continued Examination Under 37 CFR 1.114

A request for continued examination under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action has been withdrawn pursuant to 37 CFR 1.114. Applicant's submission filed on 4/11/2006 has been entered.

Response to Amendment

Amendment filed 3/9/06 has been entered and considered by the Examiner. Currently, claims 1-16 are pending in the instant application.

Allowable Subject Matter

Claims 1-16 are allowed.

The following is an examiner's statement of reasons for allowance:

Regarding claim 1, the reference of the Prior Art of record fails to teach or suggest the combination of the limitations as set forth in claim 1, and specifically comprising the limitation: a discharge light-emitting device comprising: a first substrate with at least two first electrodes formed in

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parallel to each other and configured to form a first clearance between the at least two first electrodes, a second substrate with at least two second electrodes formed on the second substrate in parallel to each other and configured to form a second clearance between the at least two second electrodes, the at least two first electrodes and the at least two second electrodes are opposite to each other and the at least two second electrodes are inside the discharge space; at least two first fluorescent layers formed on a discharge space side of the first substrate in parallel to each other so as to be opposite to the at least two first electrodes relative to the first substrate and configured to form a third clearance between the at least two first fluorescent layers, and at least two second fluorescent layers formed on a discharge space side of the second substrate in parallel to each other so as to correspond to the at least two second electrodes and configured to form a fourth clearance between the at least two second fluorescent layers, in combination with the remaining features of the claim.

Regarding claims 2-11, claims 2-11 are allowable for the reasons given in claim 1 due to their dependency status from claim 1.

Regarding claim 12, the reference of the Prior Art of record fails to teach or suggest the combination of the limitations as set forth in claim 12, and specifically comprising the limitation a discharge light-emitting device comprising: a first substrate with at least two first electrodes formed on said first substrate in parallel to each other and configured to form a first clearance between the at least two first electrodes, a second substrate with at least two second electrodes formed on the second substrate in parallel to each other and configured to form a second clearance between the at least two second electrodes, the at least two first electrodes and the at least two second electrodes are opposite to each other and the at least two second electrodes are inside a discharge space; at least two first fluorescent layers formed on a discharge space side of the first substrate in parallel to each other so as to be opposite

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to the at least two first electrodes relative to the first substrate and configured to form a third clearance between the at least two first fluorescent layers; and at least two second fluorescent layers formed on a discharge space side of the second substrate in parallel to each other so as to correspond to the at least two second electrodes and configured to form a fourth clearance between the at least two second fluorescent layers, wherein the third clearance is shorter than the fourth clearance, in combination with the remaining features of the claim.

Regarding claim 13, claim 13 is allowable for the reasons given in claim 12 due to its dependency status from claim 12.

Regarding claim 14, the reference of the Prior Art of record fails to teach or suggest the combination of the limitations as set forth in claim 14, and specifically comprising the limitation a contact image sensor comprising: a first substrate with at least two first electrodes formed on said first substrate in parallel to each other and configured to form a first clearance between the at least two first electrodes, a second substrate with at least two second electrodes formed on the second substrate in parallel to each other and configured to form a second clearance between the at least two second electrodes, the at least two first electrodes and the at least two second electrodes are opposite to each other and the at least two second electrodes are inside a discharge space; at least two first fluorescent layers formed on a discharge space side of the first substrate in parallel to each other so as to be opposite to the at least two first electrodes relative to the first substrate and configured to form a third clearance between the at least two first fluorescent layers, and at least two second fluorescent layers formed on a discharge space side of the second substrate in parallel to each other so as to correspond to the at least two second electrodes and configured to form a fourth clearance between the at least two second fluorescent layers, in combination with the remaining features of the claim.

Regarding claims 15 and 16, claims 15 and 16 are allowable for the reasons given in claim 14 due to their dependency status from claim 14.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. Takeda et al (US 20040178731) and Minamoto et al (US 20050194903) disclose similar inventions with a later filing date.

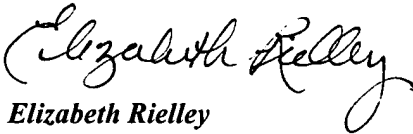
Any inquiry concerning this communication or earlier communications from the examiner should be directed to Elizabeth A. Rielley whose telephone number is 571-272-2117. The examiner can normally be reached on Monday - Friday 7:30 - 4:00.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Nimeshkumar Patel can be reached on 571-272-2457. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available

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through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).



Elizabeth Rielley

Examiner

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**MARICELI SANTIAGO
PRIMARY EXAMINER**